# 2SA1762

## Silicon PNP epitaxial planar type

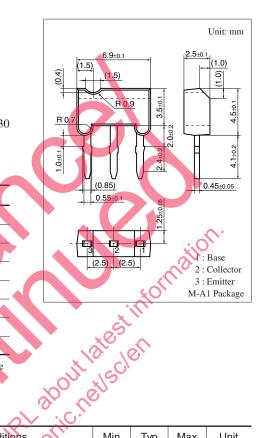
For low-frequency driver amplification Complementary to 2SC4606

#### Features

- High collector-emitter voltage (Base open)  $V_{CEO}$
- Optimum for the driver stage of a low-frequency and 25 W to 30 W output amplifier

#### Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-80	V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-80	V
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	-5	V
Collector current	I <sub>C</sub>	- 0.5	A
Peak collector current	I <sub>CP</sub>	-1	A
Collector power dissipation *	Pc	1	W
Junction temperature	Tj	150	°C
Storage temperature	T <sub>stg</sub>	-55 to +150	°C



Note) \*: Printed circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

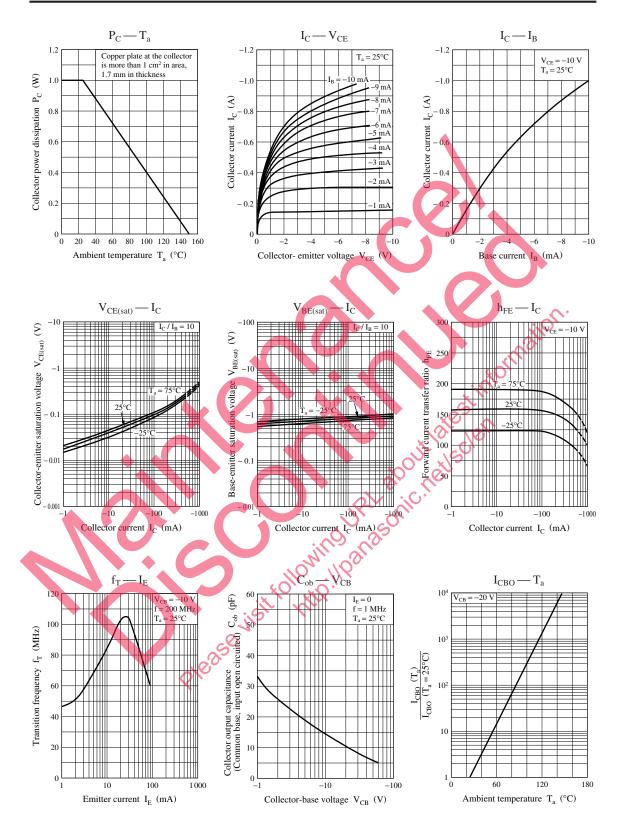
### Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

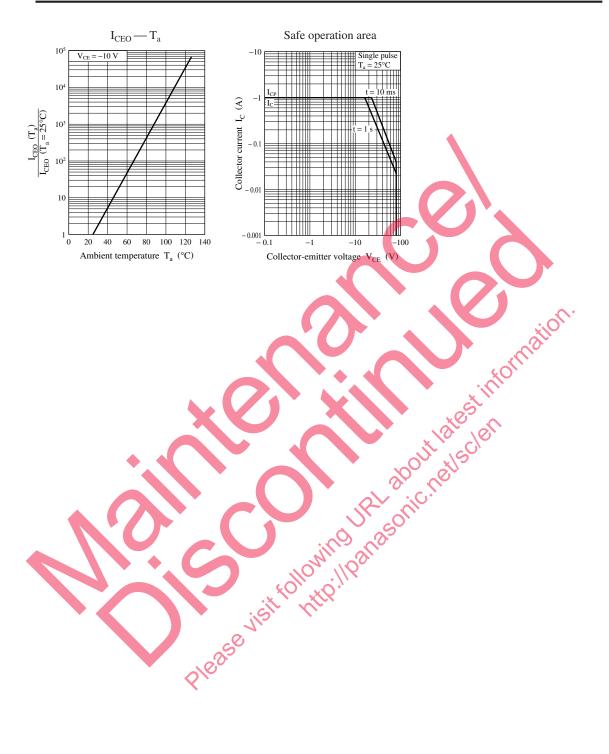
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	$I_{\rm C} = -10 \ \mu {\rm A}, I_{\rm E} = 0$	-80			V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{\rm C} = -100 \ \mu A, I_{\rm B} = 0$	-80			V
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	$I_{\rm E} = -10 \mu {\rm A},  I_{\rm C} = 0$	-5			V
Collector-base cutoff current (Emitter open)	I <sub>CBO</sub>	$V_{CB} = -20  V_{LE} = 0$			- 0.1	μΑ
Forward current transfer ratio *1	h <sub>FE1</sub> *2	$V_{CE} = -10$ V, $I_C = -150$ mA	130		330	
	h <sub>EE2</sub>	$V_{CE} = -5 \text{ V}, I_C = -500 \text{ mA}$	50	100		
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_{C} = -300 \text{ mA}, I_{B} = -30 \text{ mA}$			- 0.4	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	$I_{C} = -300 \text{ mA}, I_{B} = -30 \text{ mA}$			-1.2	V
Transition frequency	f <sub>T</sub>	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		11	20	pF
(Common base, input open circuited)						

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*1: Pulse measurement

*2: Rank classification						
Rank	R	S				
h <sub>FE1</sub>	130 to 220	185 to 330				





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